## Notice of References Cited Application/Control No. 10/624,513 Examiner FEBEN HAILE Applicant(s)/Patent Under Reexamination KAYAMA ET AL. Page 1 of 1

## U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	Α	US-7,065,183	06-2006	Raaf, Bernhard	379/74
*	В	US-7,277,721	10-2007	Okumura et al.	455/522
*	С	US-6,438,387	08-2002	Ichikawa, Yasufumi	455/522
	D	US-			
	Е	US-			
	F	US-			
	G	US-			
	Ι	US-			
	-	US-			
	٦	US-			
	K	US-			
	┙	US-			
	М	US-			

## FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
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## **NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
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\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).) Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.